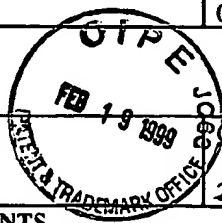


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FORM PTO-1449 US Dept. of Commerce Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)	ATTORNEY DOCKET NO.	SERIAL NO.
	ATM-337	09/200,495
	APPLICANT	
	Van Buskirk et al	
	FILING DATE	GROUP
	November 25, 1998	2812 2811



U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SA		5,783,716	7/21/98	Baum et al	556	136	
SK		5,719,417	2/17/98	Roeder et al	257	295	
		08/960,915		Hintermaier			11/20/97
SK		5,859,274	1/12/99	Baum et al	556	76	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)	
SAQ	Rossnagel, S.M. et al, "Thin high atomic weight refractor film deposition for diffusion barrier, adhesion layer, and seed Layer applications", <i>J. Vac. Sci. Technol. B.</i> Vol. 14, No. 3, May/Jun 1996 pp. 1820-1823
SK	J.L. Vossen, W. Kern, Eds., <i>Thin Film Processes II</i> , Academic Press, Boston, MA, 1991, pp. 763

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EXAMINER	DATE CONSIDERED
<i>Shaneley</i>	4/12/00

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

FORM PTO-1449 US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO. 2771-337		SERIAL NO. 09/200,495			
INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)		APPLICANT VAN BUSKIRK et al.					
		FILING DATE November 25, 1998		GROUP 2811			
		U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Soll	IA	5,561,307	10/1/96	Mihara et al.	257	295	/
SD	IB	5,736,422	4/7/98	Lee et al.	437	201	
Sf	IC	5,751,540	5/12/98	Lee et al.	361	321.4	
Sle	ID	6,002,150	12/14/99	Gardner et al.	257	310	
Sve	IE	6,005,274	12/21/99	Gardner et al.	257	411	
SR	IF	5,043,049	8/27/91	Takenaka	204	192.15	
Sle	IG	5,189,503	2/23/93	Suguro et al.	257	310	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)							
EXAMINER <i>Shunrao Hsu</i>					DATE CONSIDERED 9/26/00.		
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